

Surface Charging

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Introduction

- ~ 50 % of the space system anomalies related to space environments due to charging (internal or surface)
- Surface charging related to low energy electrons and ions (< 100 keV) that deposit their charge on covering materials
 - Plasma Spacecraft interactions prevail (collection and emission)
 - 'Absolute charging' defines potential difference bw SC and plasma
 - 'Differential charging' defines the voltage between adjacent materials
 - Large absolute charging may induce large differential charging that may induce electrostatic discharges (ESDs)
- Objectives
 - Define 'severe' and 'extreme' environments leading to ESD risks
 - Propose updates of mitigation guidelines wrt to current practices
- Outline
 - Charging assessment by numerical simulation
 - 'Severe' environments
 - 'Extreme' environments
 - Mitigating surface charging





Charging assessment by numerical simulation

- Spacecraft Plasma Interaction Software: open source, www.spis.org
- 3D Telecom spacecraft model



Mateo-Velez, Theillaumas et al. 2015



- Material properties from literature and from ONERA measurements (see **Radiation Experiments and New Materials**)
- ESD risk indicator
 - Inverted Potential Gradient (<u>IPG</u>): negative conductor nearby a less negative insulator, known to generate primary ESDs
 - Representative of major risk on solar arrays: secondary arcing
 - Identify 'severe' and 'extreme' environments → SPACESTORM project

in synergy with CNES R&D





- ONERA/CNES R&D activities : analysing 15 years of LANL data at GEO
 - e-/p+ : 100 eV up to 4-6 MeV
 - Three criteria used to classify 15 minutes average electron fluxes
 - Largest fluxes above 10 keVApril 5th, 2004
 - Combined large flux above 200 keV and low flux below 50 keVMay 29th, 2003
 - Combined low flux above 200 keV and large flux below 50 keVSept 3rd, 1997
 - One criterion used as a function of spacecraft potential
 - Longest period of time (tens of minutes) with potential exc. -5 kV...March 13th, 1997
 - 400 hundreds events identified in total (probably some others to come)



- The 400 LANL events have been consolidated by additional information
 - Good correlation with NOAA/POES 1% and 0.1% exceedance flux levels (see '1 in XX Year Events')
 - Solar wind and geomagnetic indices

~50% storm, ~50% isolated sub-storm

 \rightarrow LANL Data base is robust

- 'Low Energy Electrons' IMPTAM model used to
 - Compare 4 LANL worst events at GEO : good agreement on electrons
 - Unique tool to predict radiation belts < ~ 200 keV where few measurements are available
 - Focus on GNSS orbits L = 4.6









IMPTAM flux at GEO

ECSS-E-ST-10-04C

100

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1000

• Example of event on April 5th, 2004



• Example of Telecom spacecraft charging under the env. of April 5th, 2004



Recommendations on 'Severe' environments from standards

- ECSS and NASA standards worst-cases are very conservative at GEO
- At GEO, we recommend to use
 - ECSS-E-ST-10-04C: double maxwellian fit of SCATHA April 24th, 1979 event, which overestimated the actual data
 - NASA-HDBK-4002A: 90th percentile GEO
- At GEO, we suggest to use
 - LANL events: April 5th, 2004; May 29, 2003; Bastille day; Halloween...
 - Tri-maxwellian fit of SCATHA April 24th, 1979
- At MEO, we recommend to use ECSS worst-case
- Worst charging situations combine severe environments above and eclipse
 - Recommend charging assessment at eclipse exit
 - Combined effect of cold materials and return of photoemission process





Nowcast surface charging indicator

- Additional statistical analysis of the 15 years of LANL data also showed a good agreement between spacecraft charging and 10-50 keV electron fluxes
- Used to define risks levels at GEO (See Risk Indicators Website)
 - e- $Flux_{10-50keV} > 10^8 \text{ cm}^{-2}.\text{s}^{-1}.\text{sr}^{-1}$:
 - e- $Flux_{10-50keV} > 4 \times 10^7 \text{ cm}^{-2}.\text{s}^{-1}.\text{sr}^{-1}$:
 - e- $Flux_{10-50keV} > 1.5 \times 10^7 \text{ cm}^{-2}.\text{s}^{-1}.\text{sr}^{-1}$:
 - Otherwise:

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High Risk Level Significant Risk Level Moderate Risk Level Low Risk Level

	Internal Charging	Surface Charging	Ionising Dose	Solar Cells
GOES East	1	1	1	1
GOES West	1	1	2	1
Giove-A	1	Not available	1	1
Slot Region 8,000 km	1	Not available	3	4

Risk Indicators



'Extreme' environments

- July 23-24, 2012 extreme event
 - Extremely fast CME that missed the Earth
 - IMPTAM simulation to assess 'extreme' magnetosphere fluxes
 - <u>Initial phase:</u> Maximal electron flux (<100 keV) would be about one order of magnitude larger than LANL, NASA and ECSS worst case... during minutes
 - Main phase/Recovery phase: electron loss due to stretched B-field lines; probably no additional surface charging



- IPG of +2600 V at GEO and +3200 V at MEO within 20 seconds: huge ESD risk
- Recommend to use July 23-24, 2012 for surface charging in 'extreme' conditions

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Mitigating the risk

• ECSS and NASA guidelines to avoid ESD and detrimental effects (in brief)

• Bound/ground surface metallic parts

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- For non-conducting surfaces, if feasible, use thin conductive covering layers such as ITO
- Protect electronic equipment against EMC induced by external ESD
- Protect power systems against secondary arcing, especially solar arrays
- Alleviate negative charging : Counterbalance electron collection by electron emission using field-effect emission devices





Passive electron emitter

1. Propose a general design





3. Assess efficieny in spacecraft charging environment





Samples

- Anode
 - Dielectric material charged passively and freely by environment
 - Better if covered with appropriate thin layer
- Cathode

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- Nano technology material
- Increases the microscopic electric field and field-effect emission
- Active area ~ 0.1 cm².





Test facility

- Testing in a new ONERA vacuum chamber called PHEDRE
 - 1e-7 mbar
 - 55*60 cm
 - Heating/Cooling support
 - Charging by VUV and/or electron beam
 - Complete DAQ system (X-Y surface potential, ESD monitor, electron emission, etc)









Passive emission assessment

- Current-voltage assessment
 - High impedance circuit (10 M Ω): -14 ± 1 µA at V_bias = -500 V
 - Low impedance circuit (1 M Ω) : -29 ± 5 µA at V_bias = -500 V
 - Saturation around -30 µA



- Field-effect current of 10-30 µA (10³ times the charging photocurrent !)
- No ESD was triggered within several hours of operation





Spacecraft charging assessment

Assessment of efficiency at spacecraft level with SPIS







Spacecraft charging assessment

- Emitters to be located close to the extremity of solar arrays (from ESA/ONERA activity on Passive electron emission Co 4000105753/12/NL/KML)
- Emitted current as a function of local IVG, from experimental results
- ECSS worst case environment at Sun
 - Frame : 6 000 V
 - IVG : + 3 000 V
- At Sun with 1 emitter (estimated area ~1 cm²)
 - Frame : 5 500 V
 - IVG : + 2 200 V
- At Sun with 10 emitters (estimated area ~10 cm²)
 - Frame : 950 V
 - IVG : + 500 V







Summary - Contribution to European Space Industry

- 'Severe' environments to be used within ECSS WG on E-HB-20-06A
 - For a spacecraft surface charging estimation to be conservative at GEO, it is recommended to use ECSS or NASA 90th worst-case; with possibility to use LANL worst-cases and ECSS suggested adaptations
 - To be conservative at MEO, it is recommended to use ECSS worst case
 - Consider eclipse exit as a worst scenario
- 'Extreme' conditions such as the event on July 23, 2012 that missed the Earth would increase the ESD risk by a factor of five wrt ECSS worstcase, both at GEO and at MEO
- Additional mitigation techniques need to be implemented
 - This project showed the feasibility to use field-effect : important inputs to ESA plans to manufacture passive electron emitters
 - Further efforts are required to manufacture testable and qualifiable prototypes (need to improve cathode material and anode mounting)





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